SS-100
Micropositioner data sheet

SS-100 is a high-precision Micropositioner designed for semiconductor device detection. It has independent X, Y, Z adjustment travel of 12mm, linear motion, back lash free movement. lead screw accuracy of 100 TPI (100 screws per inch), Resolution is better than 0.7um. It is widely used in semiconductor device internal circuit characteristic analysis, failure analysis, high-frequency test, DC, photoelectric sub-micron and large I / O pad measurement.

FEATURES

>Sub-Micron internal circuit probing

>Three axis linear motion

Backlash free movement

>Flexible mount with SEMISHARE various probe arm (Coaxial/Triaxial/Kelvin/RF/ Optical arms)

>0-30° Probing inclination (Option)

>Vacuum, Magnetic and Locking screw based

>Four direction RF Probe Positioner : East / West / South / North

●RF test capability : DC to 40GHz~120GHz

●Calibration substrate with software

●45° cable connection no need for Elbow connector

●Repairable Probe head

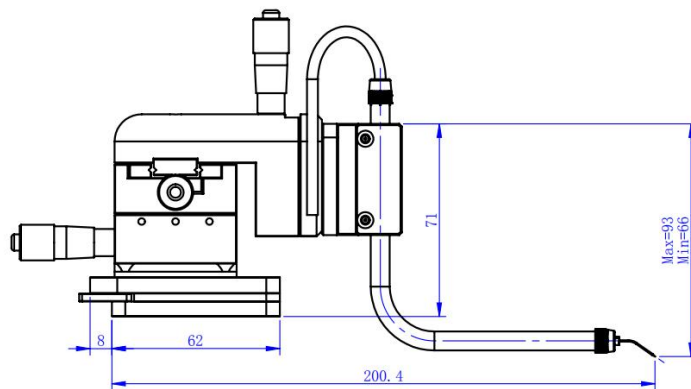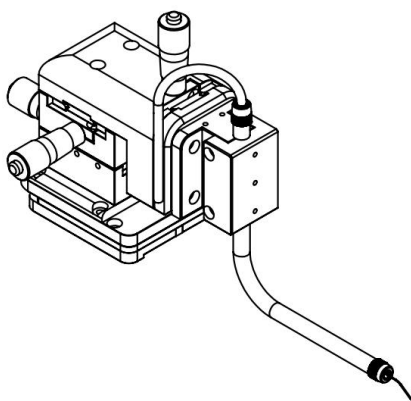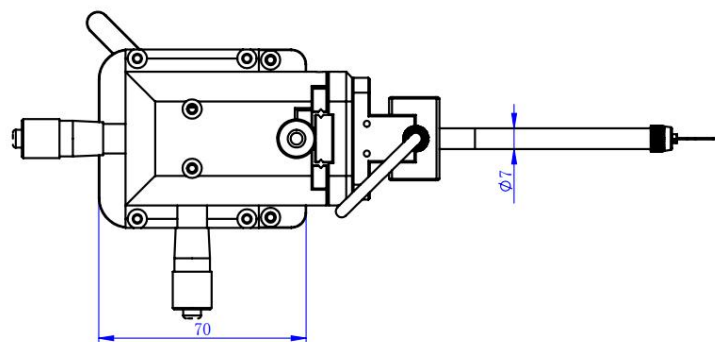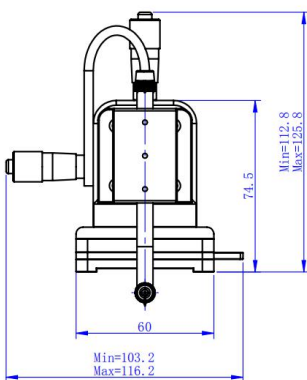>Ideal for internal probing (> 1μm) as well as large I/O pads

SPECIFICATIONS

X,Y,Z Travel range :	12 x 12 x 12 mm (linear motion)
Feature resolution：	0.7 pm
Screw resolution:	100 TPI (threads per inch)
Mounting:	Vacuum, Magnetic
Dimensions:	115*100*1125mm(L, W, H)
Weight：	1000g
Applications:	High precision and high resolution probing, internal device characterization, Failure Analysis, High Frequency, Emission Microscopy, Nanotechnology

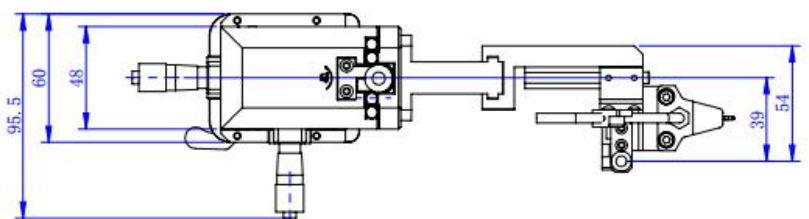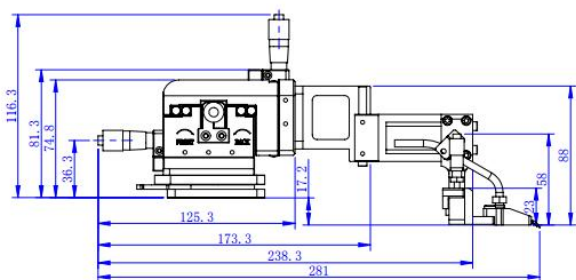Note: Data and specifications vary depending on probe system configurations and accessories
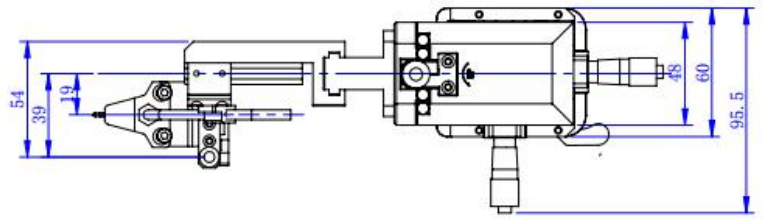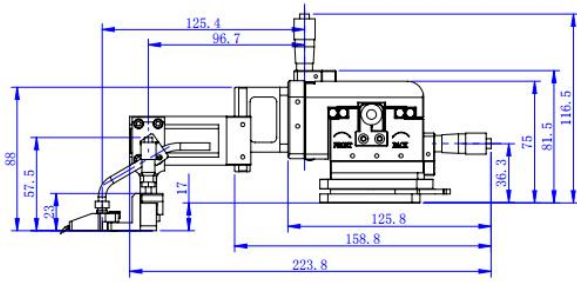
ACCESSORIES   AVAILABLE

>Triaxial arm holders with cables (Arm holders shape available in "L","H", Tubular）

>Coaxial arm holders with cables (Arm holders shape available in "L","H", Spring Holder）

>Kelvin arm holders with cables

>RF arm holders with cables

>Soft/hard probe tip, kelvin probe, RF probe, High Current Mult Probe Tip.

DIMENSIONS-DC arm
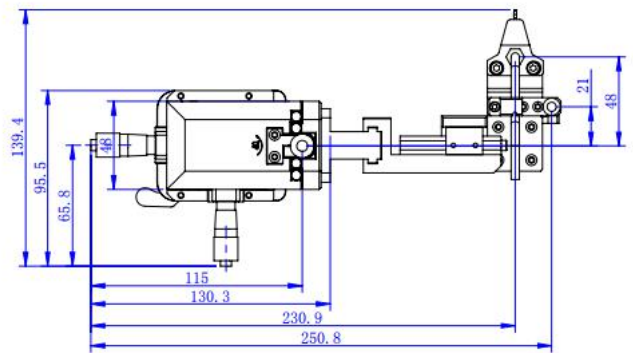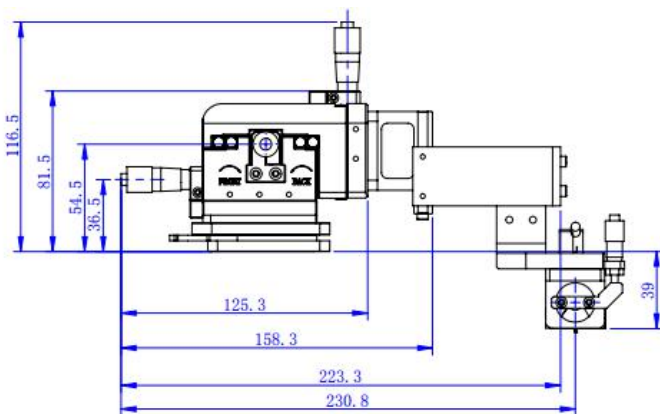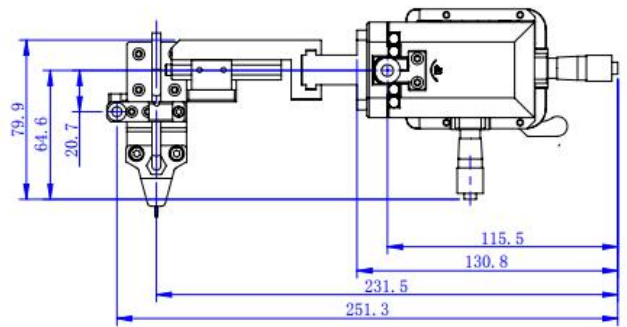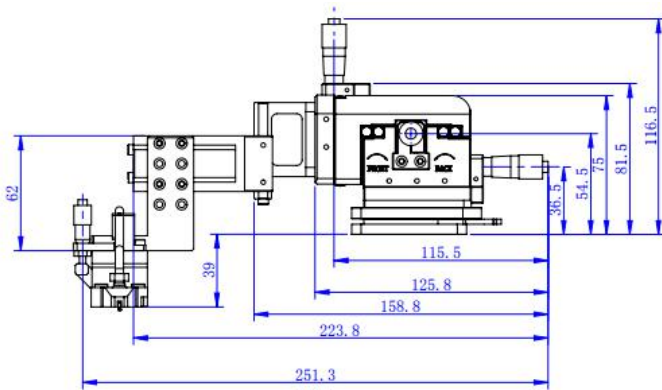

DIMENSIONS-RF arm(E/W-Turn Left&Right)

DIMENSIONS-RF arm(N/S-Turn Left&Right)